Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | LEE, KEUN-BAE | Examiner | Art Unit | Joseph F. Edell | 3636 | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0155496 A1	08-2004	Farquhar et al.	297/216.12
*	В	US-6,783,177 B1	08-2004	Nakano, Nobuyuki	297/216.12
	C	US-			
	D	US-			
	Е	US-			
	F	UŚ-			
	G	US-			
	Н	US-			
	١	US-			
	J	US-	:		
	К	US-	-		
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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